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Form PTO-1449 (Substitute) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number LAZE-01014US1	Serial/Patent Number 10/684,661
Information Disclosure Statement BY APPLICANT *(Use several sheets if necessary)*	Applicant/Patent Owner Thomas F. Rust	
	Filing/Issue Date October 14, 2003	Group Art Unit ~~2861~~ 2827

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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

*1 = Copy not submitted because it was submitted in prior application SN _/_____, filed _____, 20___, relied on under 35 USC §120.
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